Se	Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/502,296	ADACHI ET AL.
Examiner	Art Unit
Sow-Fun Hon	1772

	SEAR	CHED	
Class	Subclass	Date	Examiner
428	1.1,1.3	1/4/2007	SH
	1.5		
	1.53-1.55		
	343,349		
	355R		
	355EP		
	355N		
	355AC		
	355CN		
349	117-119		
	122		
252 1	299.01		
厂厂	299.7		

INTERFERENCE SEARCHED					
Class	Subclass	Date		Examiner	
252	299.01	1/4/2007		SH	
	299.7				
349	117-119				
349/122			_		_

	DATE	EXMR	
EAST(USPGPUB;USPAT;USOCR;JPO; DERWENT) Text search history attached	1/4/2007	SH	
STIC structure search report, database number 210804			
Reviewed correlated application 10/499 763			
Consulted Sean Wu, Primary in 252/299+			
Consulted Nasser Ahmad, Primary in 428/343+			
Interference search cont'd:428/1.1,1.3,1.5,1.53- 1.55,343,349,355R,355EP,355N, 355AC,355CN			